

# Decision Ordering Based Property Decomposition for Functional Test Generation

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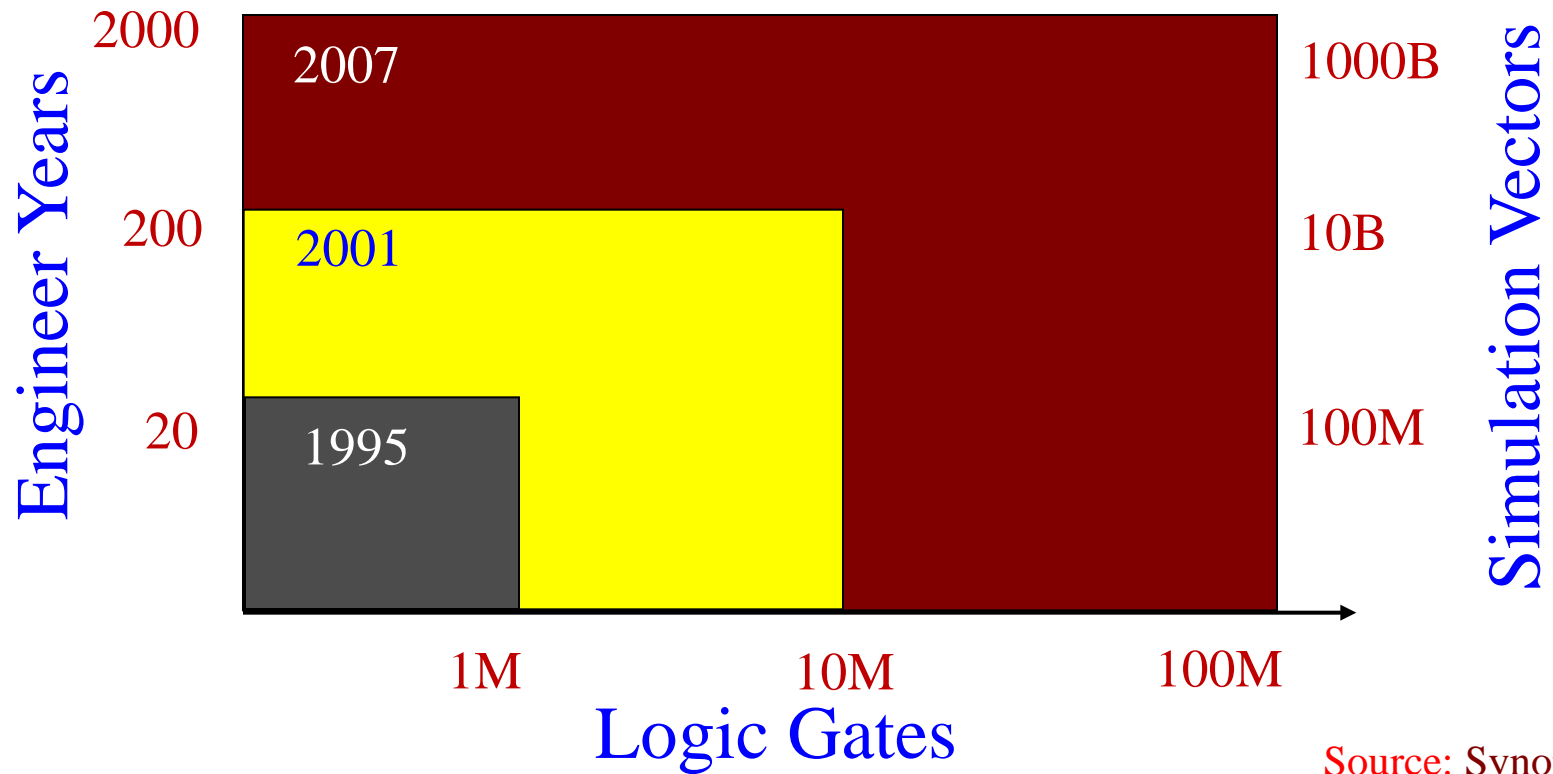
# Outline

- Introduction
- Simulation-based Functional Validation
  - ◆ Test Generation using Model Checking
  - ◆ Test Generation using SAT-based BMC
- Test Generation using Decision Ordering
  - ◆ Learning-oriented property decomposition
  - ◆ Decision ordering based learning techniques
  - ◆ Test generation using our methodology
- Experiments
- Conclusion

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# Functional Validation of SoC Designs



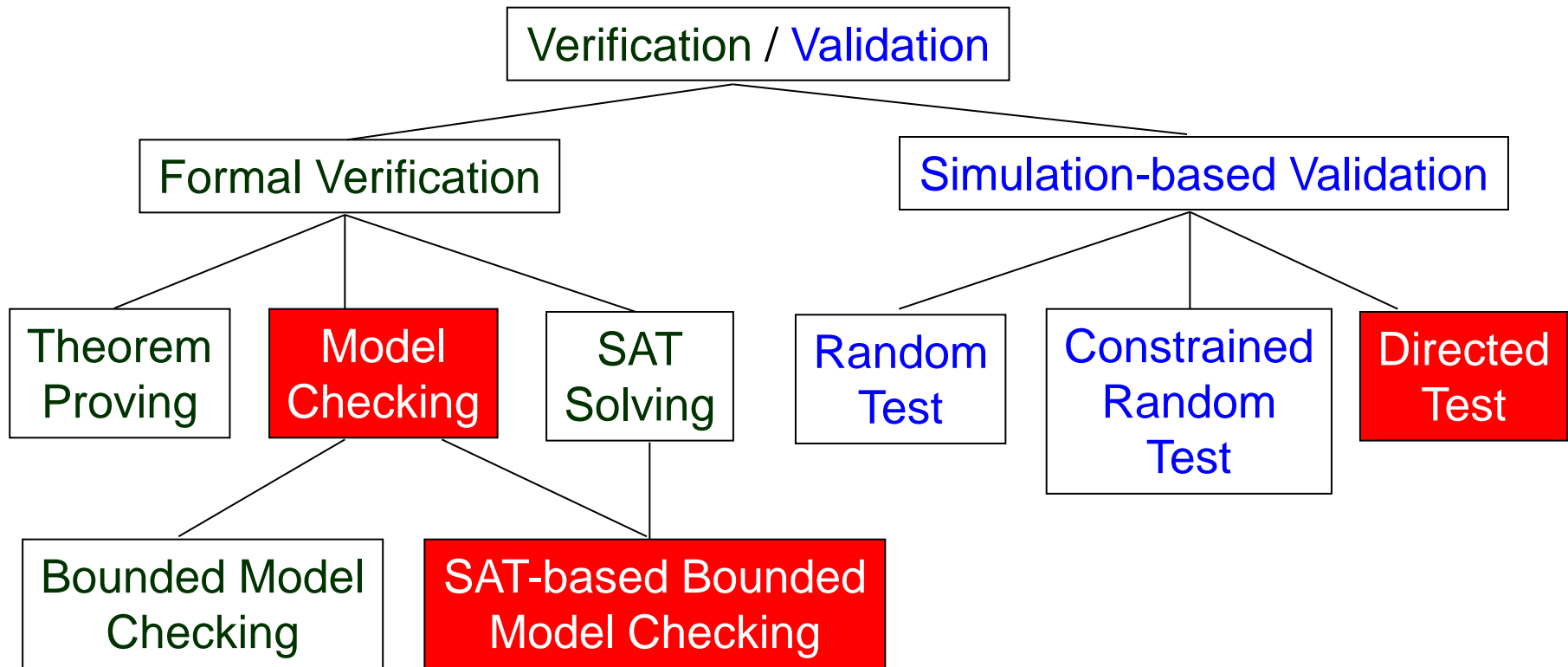
Source: Synopsys

- Functional validation is a major challenge
  - ◆ Majority of the SoC fails due to logic errors
- Simulation using directed tests is promising

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# Automated Directed Test Generation



Directed test generation based on the automation of model checking techniques.

# Test Generation using Model Checking

- **Model Checking**
  - Designs are in formal specifications, e.g., SMV
  - Desired behaviors in temporal logic properties
  - Property holds, or fails with a counterexample

**Problem:** Test generation is very costly or not possible in many scenarios in the presence of complex SoCs and/or complex properties.

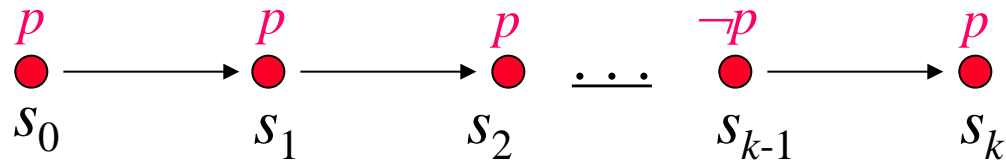
**Approach:** Exploit some learning to reduce complexity

- Reduction of TG time & memory requirements
- Enables test generation in complex scenarios

# SAT-based Bound Model Checking

- Test generation needs to consider **safety** properties
- The safety property  **$P$**  is valid up to cycle  **$k$**  iff  **$\Omega(k)$**  is not satisfiable.

$$\Omega(k) = I(S_0) \wedge \bigwedge_{i=0}^{k-1} R(S_i, S_{i+1}) \wedge \bigvee_{i=0}^k \neg P(s_i)$$

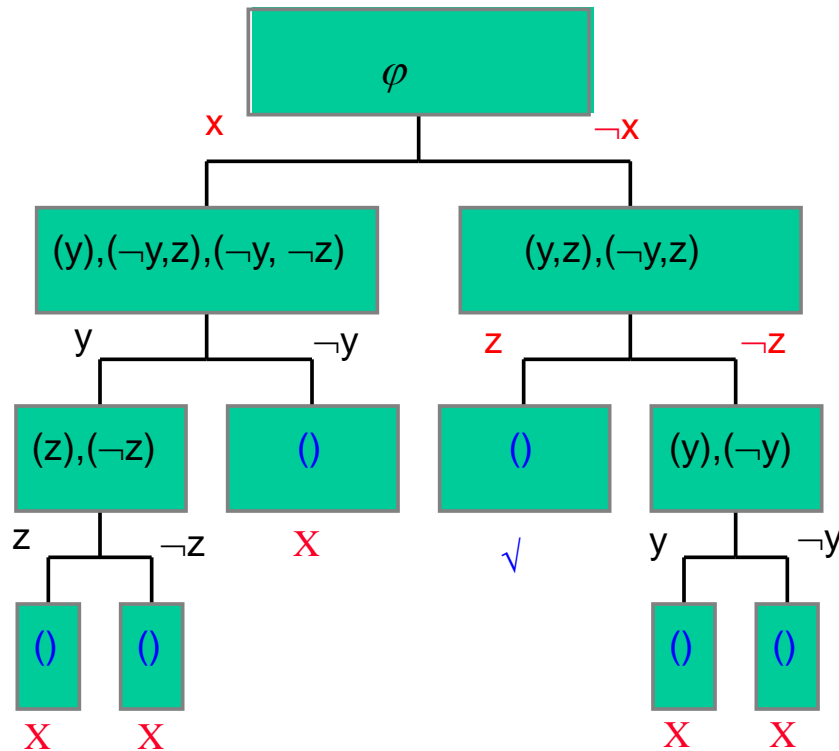


- If  **$\Omega(k)$**  is satisfiable, then we can get an assignment which can be translated to a **test**.



# Decision Ordering Problem

Given a  $\varphi$  in CNF:  $(x+y+z)(\neg x+y)(\neg y+z)(\neg x+\neg y+\neg z)$



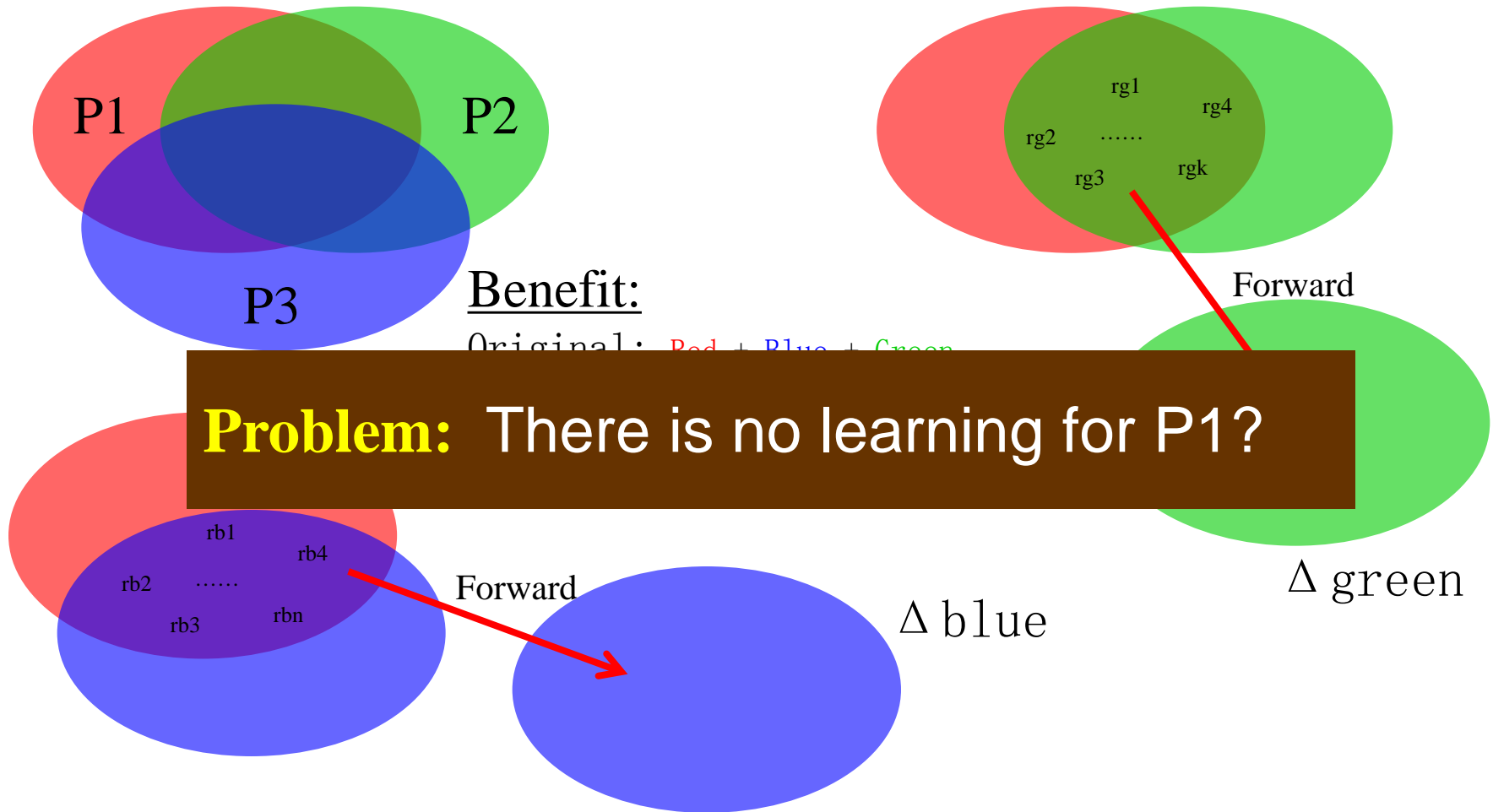
□ A wise decision ordering can quickly locate the true assignment.

❖ Bit value ordering

❖ Variable Ordering

Best decision:  $\neg x, z$

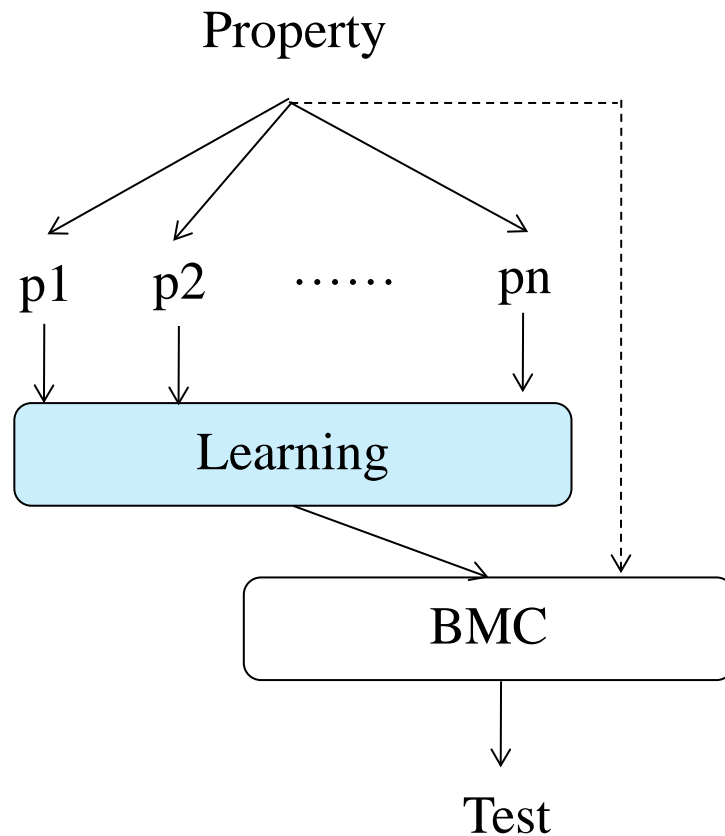
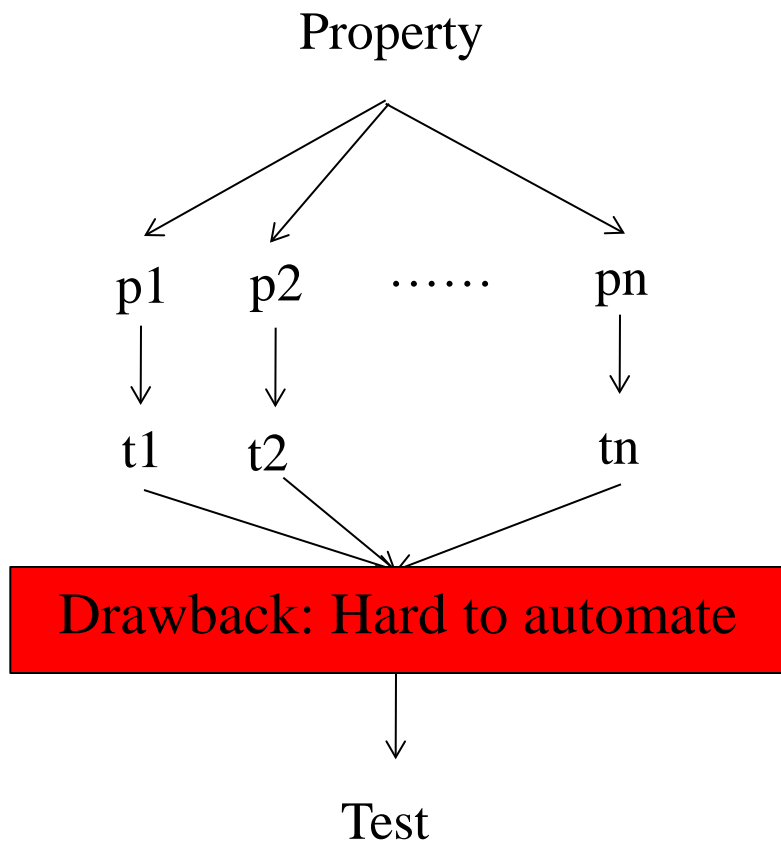
# Same Design, Different Properties



M. Chen and P. Mishra. **Functional Test Generation using Efficient Property Clustering and Learning Techniques.** *TCAD 2010.*

M. Chen and P. Mishra. **Efficient Decision Ordering Techniques for SAT-based Test Generation.** *DATE 2010.*

# Property Decomposition Technique



Koo et al. *Functional Test Generation using Property Decomposition Techniques*. ACM *TECS*, 2009

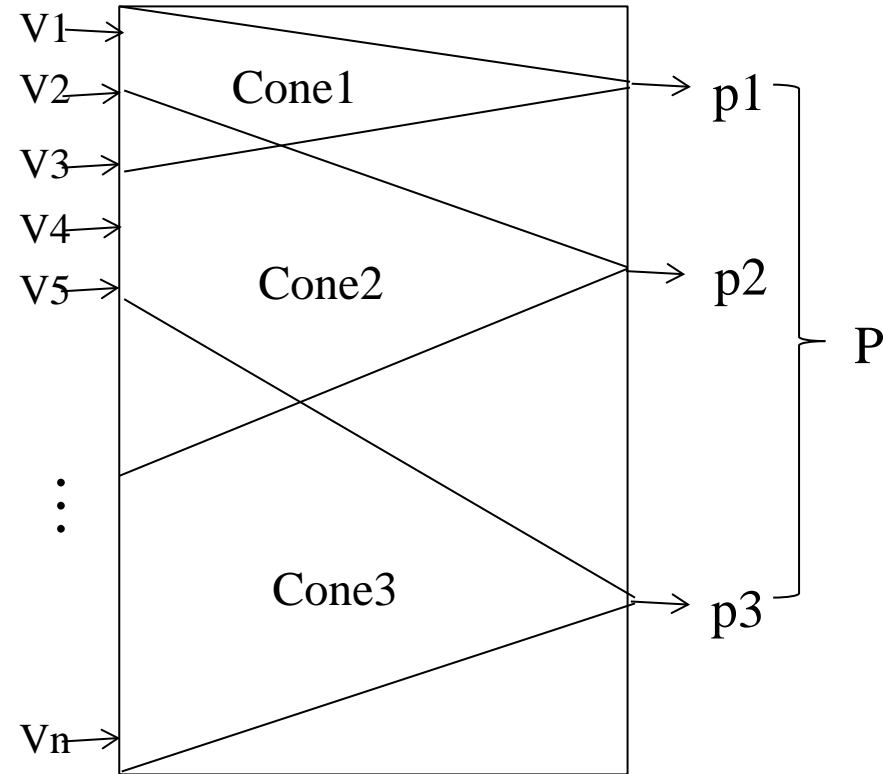
# Promising Observations

- Sub-properties may have a large overlap in counter-examples (variable assignments) with original property.
  - ◆ Such important information can be reused as a kind of decision ordering.
- The learning from sub-properties can drastically reduce the overall test generation time.
  - ◆ The SAT instance for sub-properties can be much smaller than that of original property
  - ◆ The learning from sub-properties can drastically accelerate the falsification of original property.

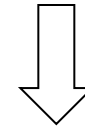
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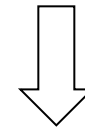
# Spatial Property Decomposition



$$\text{COI}(p_1) < \text{COI}(p_2) < \text{COI}(p_3) < \text{COI}(P)$$



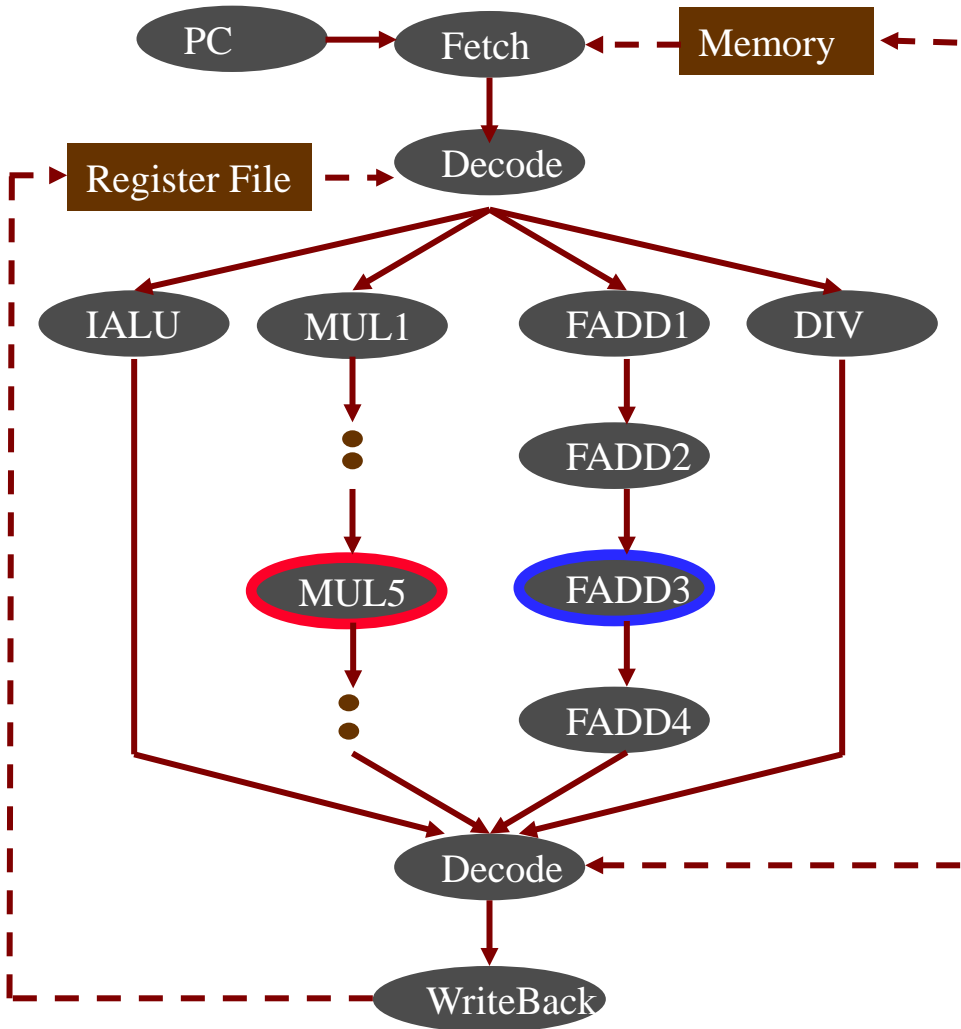
$$\text{Time}(p_1) < \text{Time}(p_2) < \text{Time}(p_3) < \text{Time}(P)$$



Learning from  $P_1$  can reduce the  $\text{Time}(P)$  ?

**Learn from the sub-properties with smaller COI.**

# A MIPS Processor Example

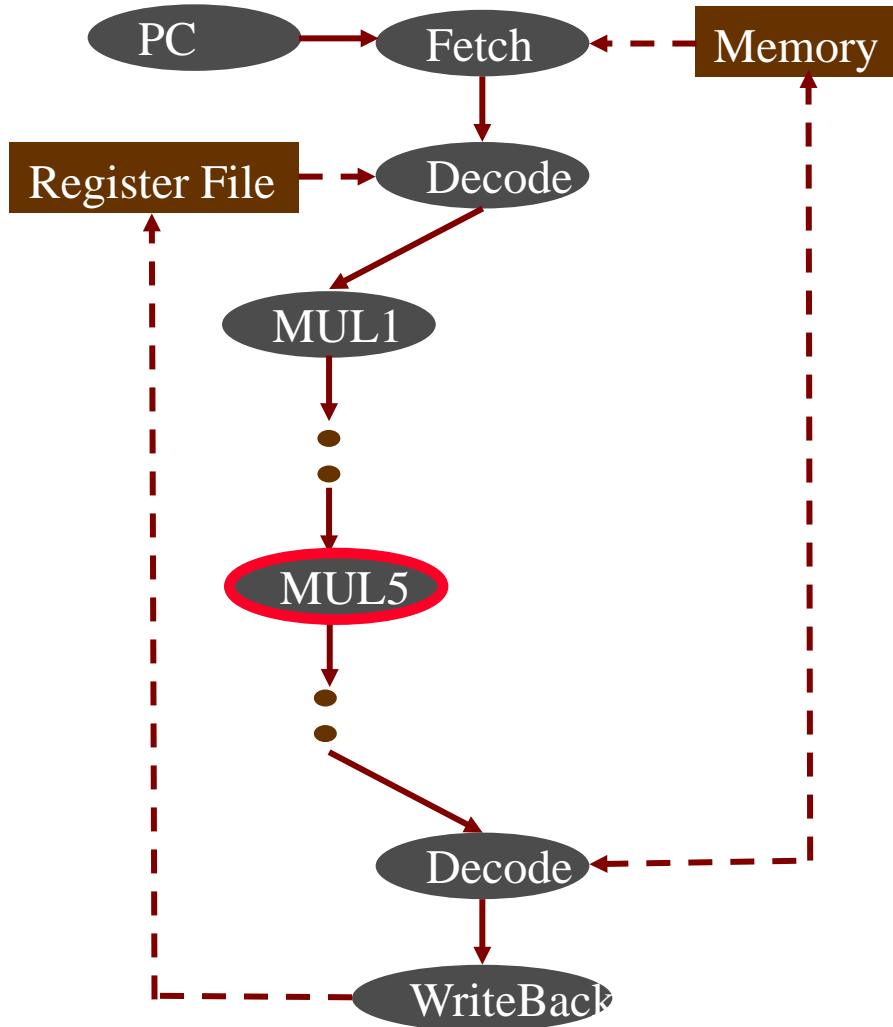


## Checked Property

P: The units MUL5 and FADD3 can be activated together at 8<sup>th</sup> clock cycle.

LTL:  $\neg F(\text{MUL5}=\text{active} \ \& \ \text{FADD3}=\text{active} \ \& \ \text{clk}=8)$

# Spatial Property Decomposition



## Checked sub Property

P1: The units MUL5 can be activated at 8<sup>th</sup> clock cycle.

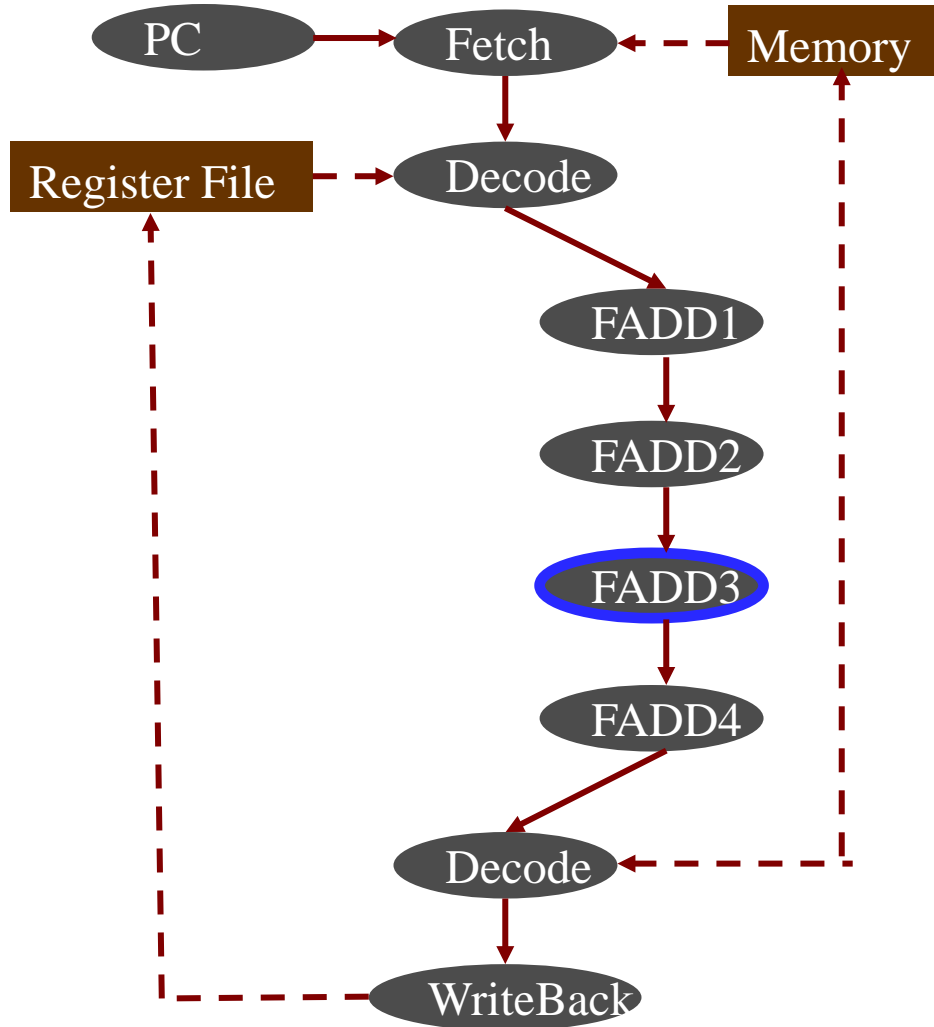
LTL:  $\neg F(\text{MUL5}=\text{active} \ \& \ \text{clk}=8)$

## Counterexample for P1

Cycles	P1's test
1	NOP
2	MUL R2, R2, R0
3	NOP
4	NOP



# Spatial Property Decomposition



Checked sub Property

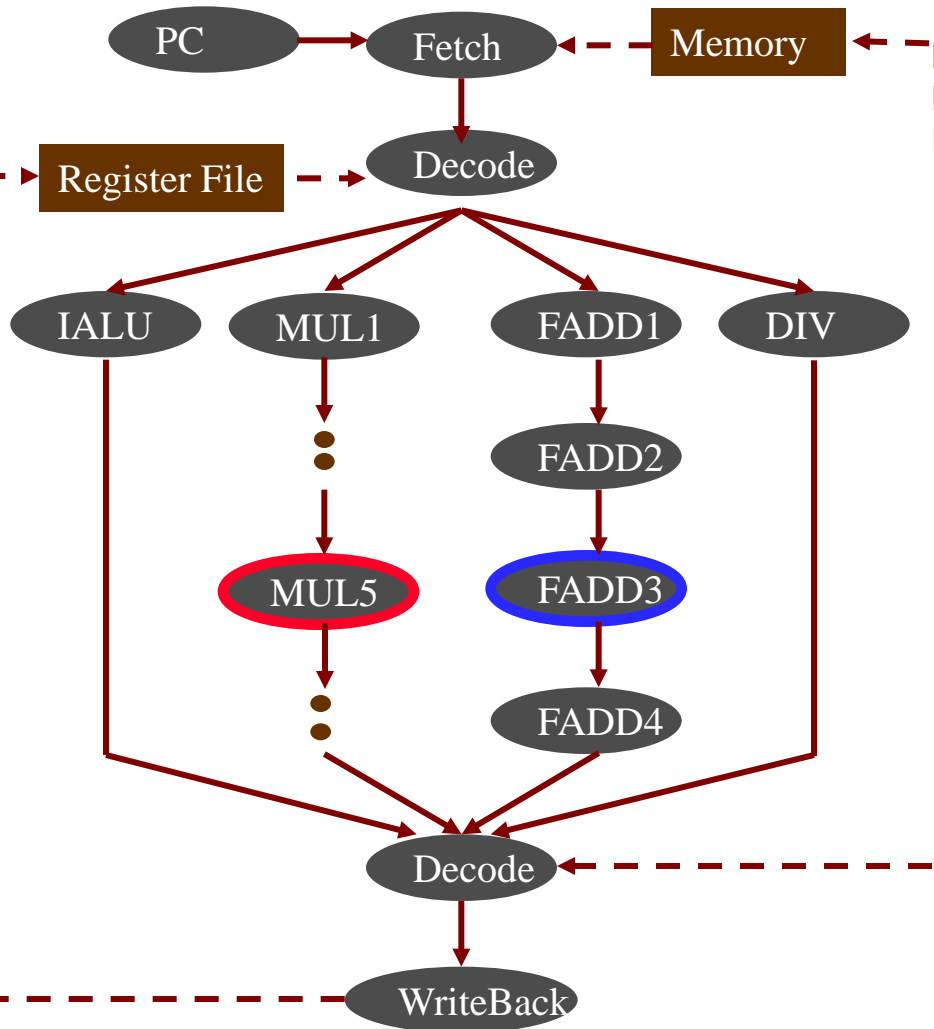
P2: The units FADD3 can be activated at 8<sup>th</sup> clock cycle.

LTL: !F(FADD3=active & clk=8)

Counterexample for P2

Cycles	P2's test
1	NOP
2	NOP
3	NOP
4	FADD R1, R1, R0

# Learning from Spatial Property Decomposition



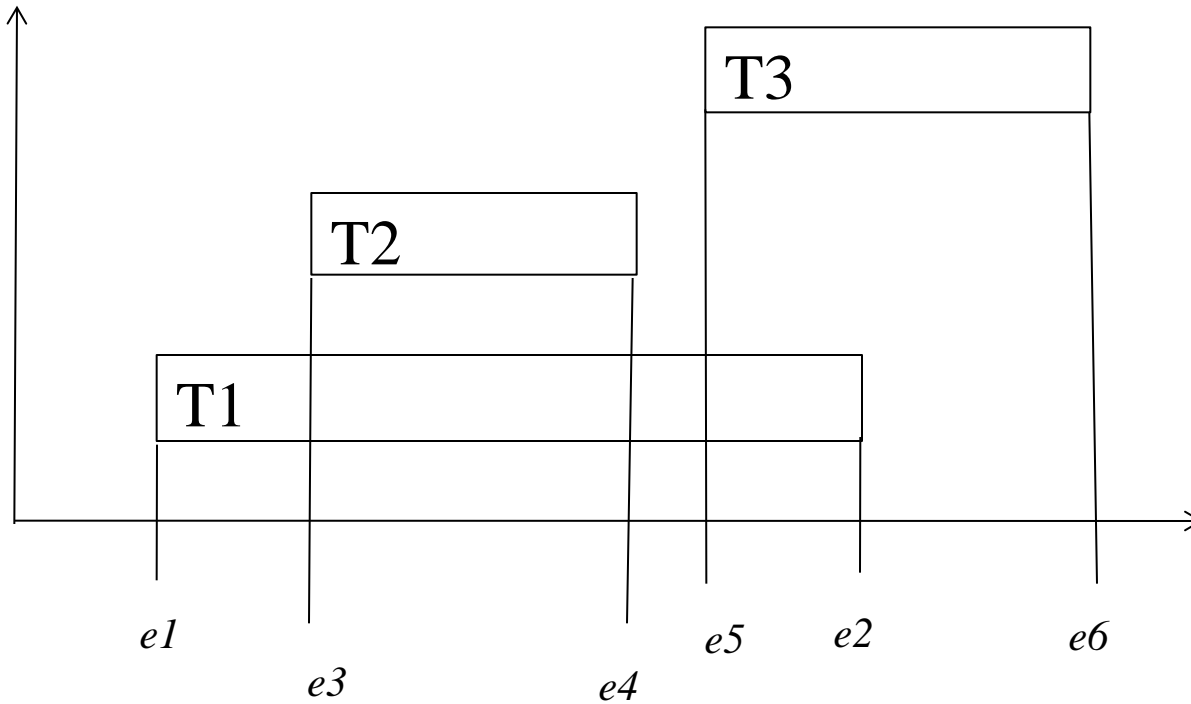
## Counterexample for P2 guided by P1

Cycles	Learning
1	NOP
2	MUL R2, R2, R0
3	NOP
4	FADD R1, R1, R0

## Counterexample for P

Cycles	Learnings
1	NOP
2	MUL R2, R2, R0
3	NOP
4	FADD R1, R1, R0

# Temporal Decomposition

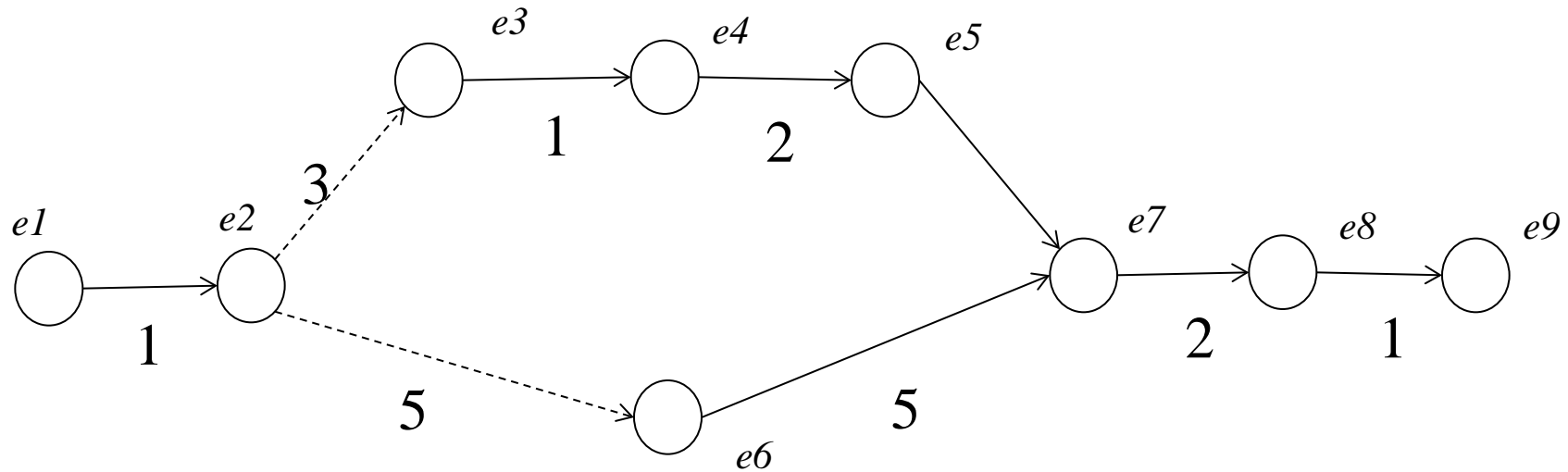


Cause effect relation:  $e1 \rightarrow e2$     $e3 \rightarrow e4$     $e5 \rightarrow e6$

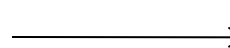
Happen before relation:  $e1 < e3 < e4 < e5 < e2 < e6$

**Learn from the sub-properties with smaller bound.**

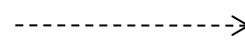
# Event Relation Analysis



event



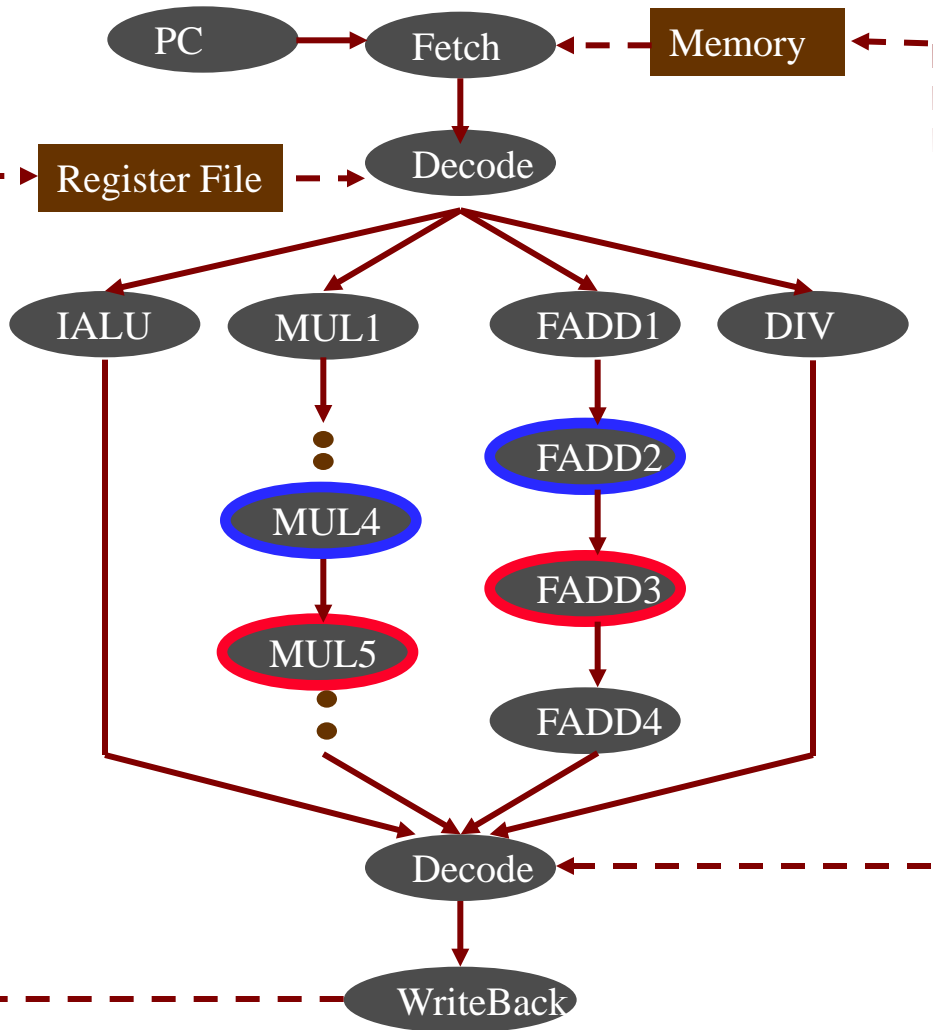
Cause-effect



Happen-before

$!F(e1) \rightarrow !F(e3) \rightarrow !F(e7) \rightarrow !F(e9)$

# A MIPS Processor Example



## Checked Property

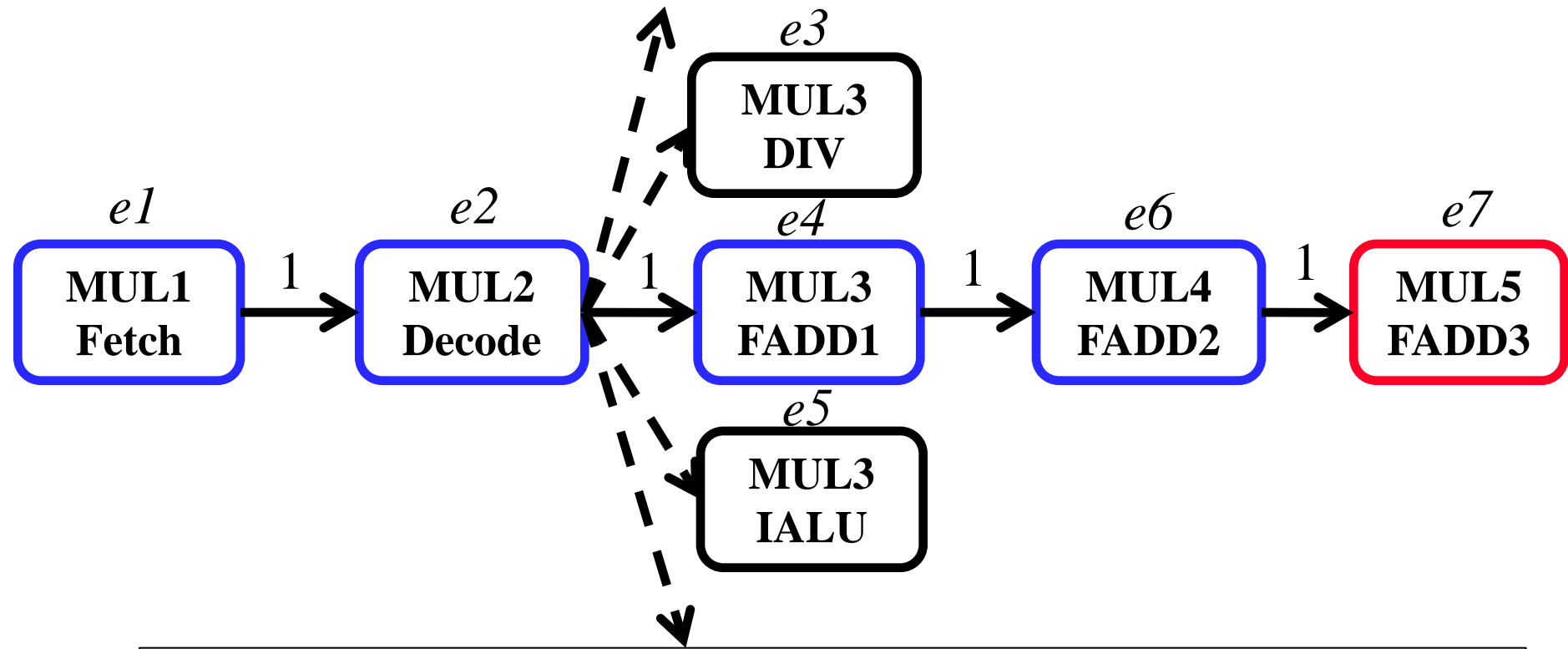
P: The units MUL5 and FADD3 can be activated together at 8<sup>th</sup> clock cycle.

LTL: ! F(MUL5=active & FADD3=active & clk=8)

## A sub-property example

LTL: ! F(MUL4=active & FADD2=active & clk=7)

# Event Relation Construction



## Original Property

$P_{e7}$ :  $\neg F(\text{MUL5=active} \ \& \ \text{FADD3=active} \ \& \ \text{clk}=8)$

## Temporally Decomposed Properties

$P_{e1}$ :  $\neg F(\text{MUL1=active} \ \& \ \text{Fetch=active} \ \& \ \text{clk}=4)$

$P_{e4}$ :  $\neg F(\text{MUL3=active} \ \& \ \text{FADD1=active} \ \& \ \text{clk}=6)$

# Decision Ordering Heuristics

- Let ***vstat[sz][2]*** be a 2-dimension array to record the statistics of sub-property results. It is used to indicate the decision ordering of unchecked properties.
- The term ***bias(vi)*** is used to indicate the variable assignment variance of ***vi***.

$$bias(vi) = \frac{\text{Max}(vstat[i][0], vstat[i][1]) + 1}{\text{Min}(vstat[i][0], vstat[i][1]) + 1}$$

# Decision Ordering Heuristics (cont.)

- Our decision ordering is **based on VSIDS** but our method considers **decision ordering learned from sub-properites.**

## Initialization

$score(li) =$  literal count of  $li$  in CNF clauses

## Periodical update (include initialization)

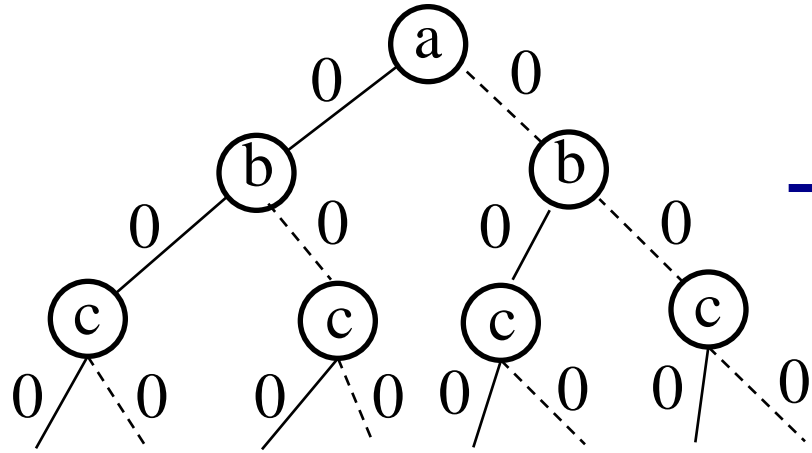
$$score(li) = \begin{cases} \max(vi) * bias(vi) & ( varStat[i][1] > varStat[i][0] \ \& \ li = vi) \\ & \text{or } ( varStat[i][0] > varStat[i][1] \ \& \ li = vi' ) \\ score(li) & \text{Otherwise} \end{cases}$$

where  $\max(vi) = \text{MAX}( score(vi), score(vi') ) + 1.$

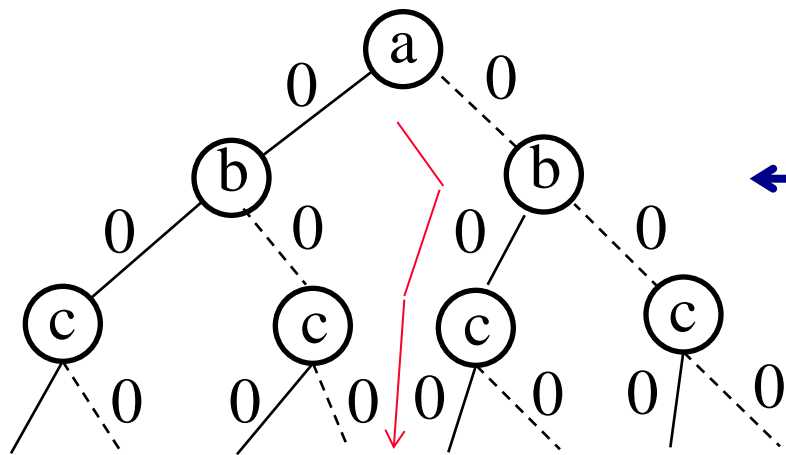
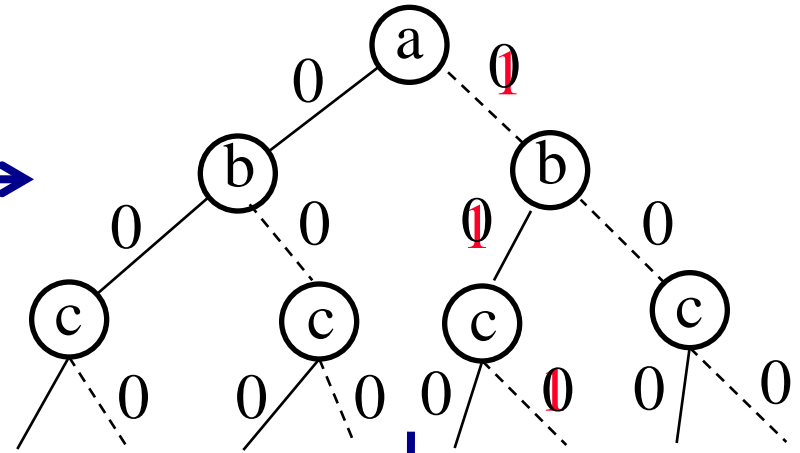


# An Example of Learning

Initialization



P1: a=0, b=1, c=0



P2: a=0, b=1, c=1

# Test Generation Using Our Method

Inputs: a) Formal model of the Design,  $D$

b) Property  $P$  and satisfiable bound  $bound_P$

c) Decomposed properties  $prop$  and satisfiable  $bounds$

Output: A test  $test_p$  for  $P$

1.  $CNFs = BMC(D, props, bounds);$
2.  $(CNF1, CNF2, \dots, CNFn) = \text{Sort CNF using increasing file size}$
3. Initialize  $vstat$ ;
4. for  $i$  is from 1 to  $n$  do
  - a)  $test_i = SAT(CNF_i, vsat);$
  - b)  $Update(vstat, test_i, bounds[i]);$endfor
5. Generate  $CNF = BMC(D, P, bound_P);$
6. return  $test_p = SAT(CNF, vstat);$

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- **Experiments**
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# Case Study 1: MIPS Processor

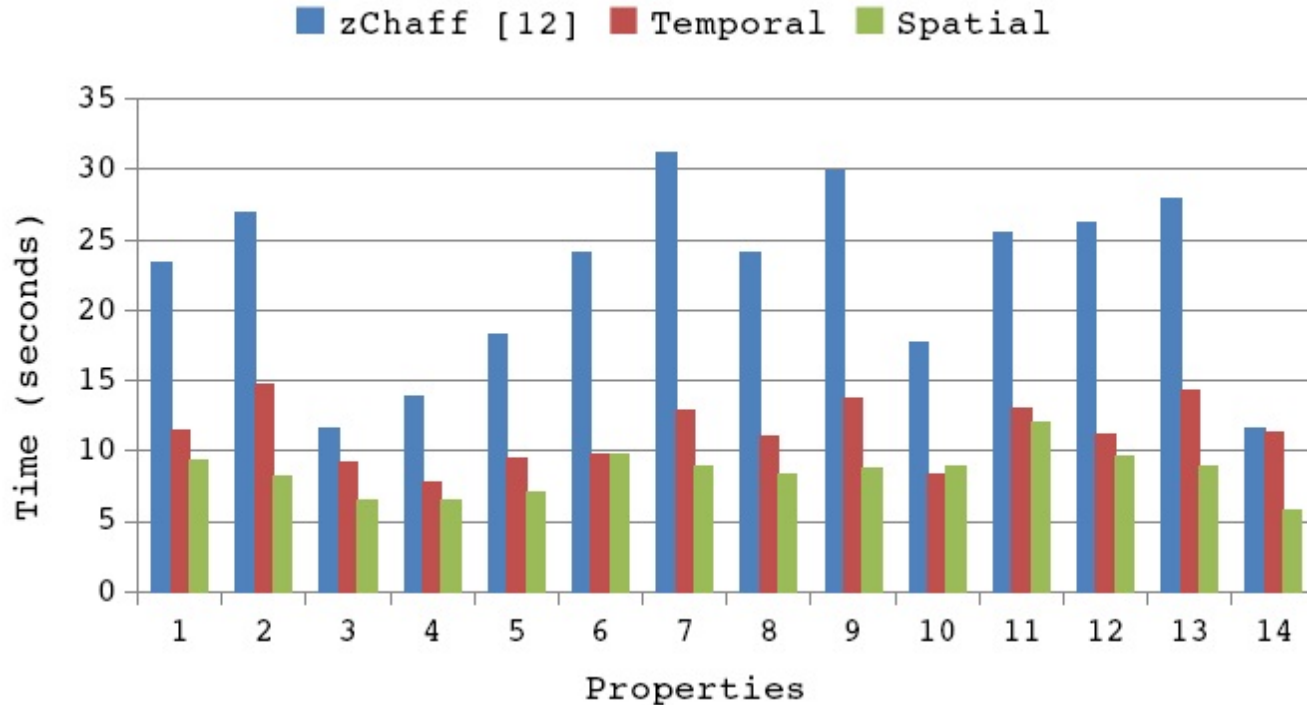
- We generated **20** properties based on interaction faults on various function unit (ALU, DIV, FADD and MUL). **6** of them cannot be handled by temporal decomposition.

Property (test)	zChaff (sec)	Num. of Clusters	Num. of Sub-props	Spatial (sec)	Speedup
P1	127.52	3	2	49.41	2.58
P2	49.24	3	2	15.73	3.13
P3	9.18	2	1	4.99	1.84
P4	13.78	2	1	7.28	1.89
P5	31.63	3	2	12.74	2.48
P6	120.72	3	2	54.21	2.23

**Speedup: 1.84-3.13 times**

# Case Study 1: MIPS Processor

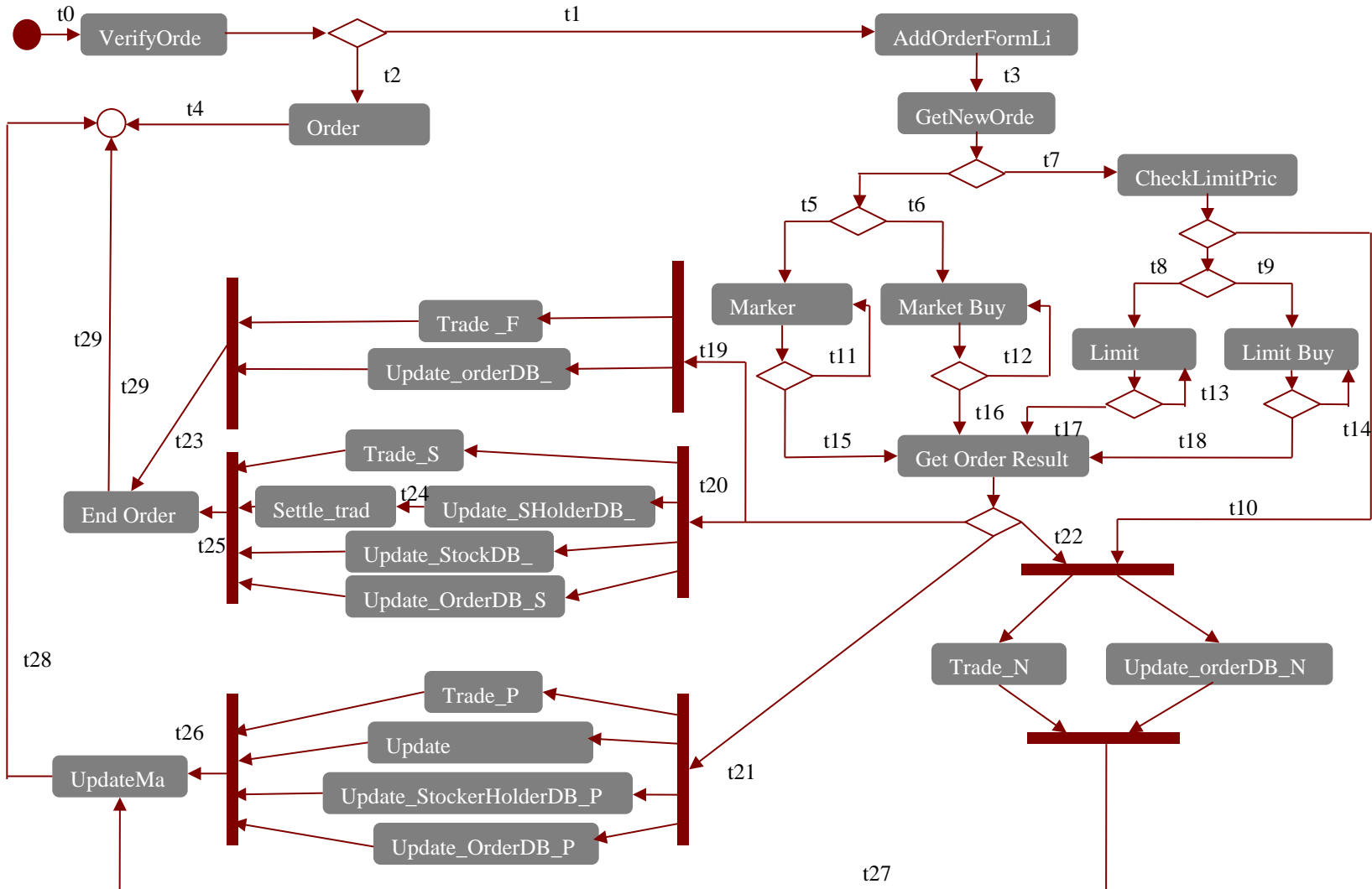
- For the remaining 14 properties, we adopt both spatial and temporal decompositions.



**Indications:** Test generation complexity is significantly improved

- Spatial decomposition is better in this example
- Temporal decomposition can still get 2.5X speedup

# Case Study 2 : OSES



# Case Study 2: OSES

- This case study is a on-line stock exchange system. The activity diagram consists of **27** activities, **29** transitions and **18** key paths.

Property	zChaff (sec)	Bound	Num. of Sub-properties	Temporal (sec)	Speedup
P1	25.99	8	3	0.78	33.32
P2	48.99	10	4	2.69	18.21
P3	39.67	11	5	3.45	11.50
P4	247.26	11	5	22.46	11.01
P5	160.73	11	5	15.68	10.25
P6	97.54	11	4	1.56	62.53
P7	31.39	10	4	12.31	2.55
P8	161.74	11	4	12.62	12.82
P9	142.91	10	4	17.57	8.13
P10	33.77	10	4	1.76	19.19

**Speedup: 3-63 times**

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# Conclusions

- **Functional validation is a major bottleneck**
  - SAT-based approaches are promising for automated test generation.
- **Proposed an efficient technique for generation of directed tests using learning techniques**
  - ◆ Developed two novel property decomposition techniques based on decision ordering learning.
- **Successfully applied on both hardware and software designs**
  - Significant reduction in overall validation effort



**Thank you !**